









# SEMI Standards Staff Report

December 16, 2015

# SEMI Global 2015 & 2016 Calendar of Events

Event Name		Event Details
	SEMICON Japan	December 16-18, 2015 Tokyo, Japan
	European 3D Summit	Jan 18-20, 2016 Grenoble, France
	SEMICON Korea	Jan 27-29, 2016 Seoul, Korea
	ISS Europe	Mar 6-8, 2016 Nice, France

# SEMI Global 2016 Calendar of Events

Event Name		Event Details
	Solarcon China SEMICON China	March 15-17, 2016 Shanghai, China
	Advanced Semiconductor Manufacturing Conference (ASMC)	May 16-19, 2016 Saratoga Spring, NY
	SEMICON West	July 12-14, 2016 San Francisco, California
	SEMICON Taiwan	September 7-9, 2016 Taipei, Taiwan
	SEMICON Europa	October 25-27, 2016 Grenoble, France

# Global Standards Meeting Schedule

<http://www.semi.org/en/node/9051>

- Dec 15-18, 2015  
SEMICON Japan Standards Meetings  
Tokyo, Japan
- Jan 27-29, 2016  
SEMICON Korea Standards Meetings  
Seoul, Korea
- Feb 5, 2016  
Assembly & Packaging Japan TC Chapter meeting  
Tokyo, Japan
- Feb 5, 2016  
3DS-IC Japan TC Chapter Meeting  
Tokyo, Japan
- April 4-7, 2016  
SEMI HQ in San Jose, California
- July 11-14, 2016  
Marriott San Francisco, California

As of Dec. 15, 2015  
Please make sure most updated  
information in the above URL

# 2016 Critical Dates for SEMI Standards Ballots

Cycle	Ballot Submission Date	Voting Period Starts	Voting Period ends
Cycle 1	January 4	January 12	February 12
Cycle 2	February 2	February 16	March 17
Cycle 3	March 1	March 14	April 13
Cycle 4	April 15	April 26	May 26
Cycle 5	May 10	May 24	June 23
Cycle 6	July 22	July 29	August 28
Cycle 7	August 17	August 31	September 30
Cycle 8	October 17	October 24	November 23
Cycle 9	November 16	November 30	December 30

# SEMI Standards Publications

Cycle	New	Revised	Reapproved	Withdrawn
July 2015	4	0	0	0
August 2015	3	9	8	0
September 2015	3	8	2	0
October 2015	2	13	5	1
November 2015	1	14	8	0

- Total SEMI Standards in portfolio: 950
  - Includes 114 Inactive Standards

# SEMI Standards Publications

- New Standards

Cycle	Designation	Title	Committee	Region
July 2015	SEMI 3D13	Guide for Measuring Voids in Bonded Wafer Stacks	3D-IC	NA
July 2015	SEMI PV64	Test Method for Determining B, P, Fe, Al, Ca Contents in Silicon Powder for PV Applications by Inductively Coupled Plasma Optical Emission Spectrometry	Photovoltaic	CH
July 2015	SEMI PV65	Test Method Based on RGB for Crystalline Silicon (c-Si) Solar Cell Color	Photovoltaic	CH
July 2015	SEMI PV66	Test Method for Determining the Aspect Ratio of Solar Cell Metal Fingers by Confocal Laser Scanning Microscope	Photovoltaic	CH
August 2015	SEMI PV67	Test Method for the Etch Rate of a Crystalline Silicon Wafer by Determining the Weight Loss	Photovoltaic	CH

# SEMI Standards Publications

- New Standards Cont.

Cycle	Designation	Title	Committee	Region
August 2015	SEMI PV68	Test Method the for Wire Tension of Multi-Wire Saws	Photovoltaic	CH
August 2015	SEMI C88	Specification for Dimension of Sandwich Components for 1.125 Inch Type Surface Mount Gas Distribution Systems	Gases	NA
September 2015	SEMI E168.2	Specification for Product Time Measurement for Material Control Systems	Information & Control	NA
September 2015	SEMI E168.3	Specification for Product Time Measurement for Transport	Information & Control	NA

# SEMI Standards Publications

- New Standards Cont.

Cycle	Designation	Title	Committee	Region
September 2015	SEMI M86	Specification for Polished Monocrystalline c-Plane Gallium Nitride Wafers	Compound Semiconductor	NA
October 2015	SEMI C90	Test Method and Specification for Testing Perfluoroalkoxy (PFA) Materials Used in Liquid Chemical Distribution Systems	Liquid Chemicals	NA
October 2015	SEMI PV69	Test Method for Spectrum Response (SR) Measurement of Organic Photovoltaic (OPV) and Dye-Sensitized Solar Cell (DSSC)	Photovoltaic	TA
November 2015	SEMI C91	Test Method for Determination of Moisture Dry-Down Characteristics of Gas Delivery Components	Cases	NA

# SEMICON Japan 2015 概要: 開催規模

カッコ内は前年実績数

- 出展者数 732 (725), 前年比101%
- 出展小間数 1,705 (1,638), 前年比104%
- 出展国数 16カ国/地域 (14)
- 来場者数 65,000 延べ数見込  
(60,211) 前年比108%
- 来年の開催日時
  - 2016年12月14日 (水) –16日 (金)
  - 東京ビッグサイト

# SEMICON Japan 2015 概要:特徴

- 展示会規模
  - － 出展小間数・社数・国数ともに昨年を上回る
- エリア別小間数
  - － 前工程ゾーン：微減
  - － 後工程・総合・材料ゾーン、WORLD OF IOT、テーマパビリオン：増
  - － ※WORLD OF IOT
    - 最終的には65社122小間(2014年58社、110小間)と、昨年を上回った。
- 海外出展者
  - － 社数で732社中119社（16%） 昨年比で7%増
- 国別
  - － 台湾・韓国の増加が顕著
  - － 米国：クリスマスの影響が心配されたが横ばい
  - － 欧州：微減。
- カスタマーサイドや金融等異業種の出展
  - － 日立製作所、富士通セミコン、シーメンス、 アマゾンウェブサービス、TESLA、みずほ銀行、JA三井リース等
- INNOVATION VILLAGE（初開催）
  - － 13のスタートアップが参加。
- 中小企業の出展
  - － IOTやパビリオンエリアに多数。

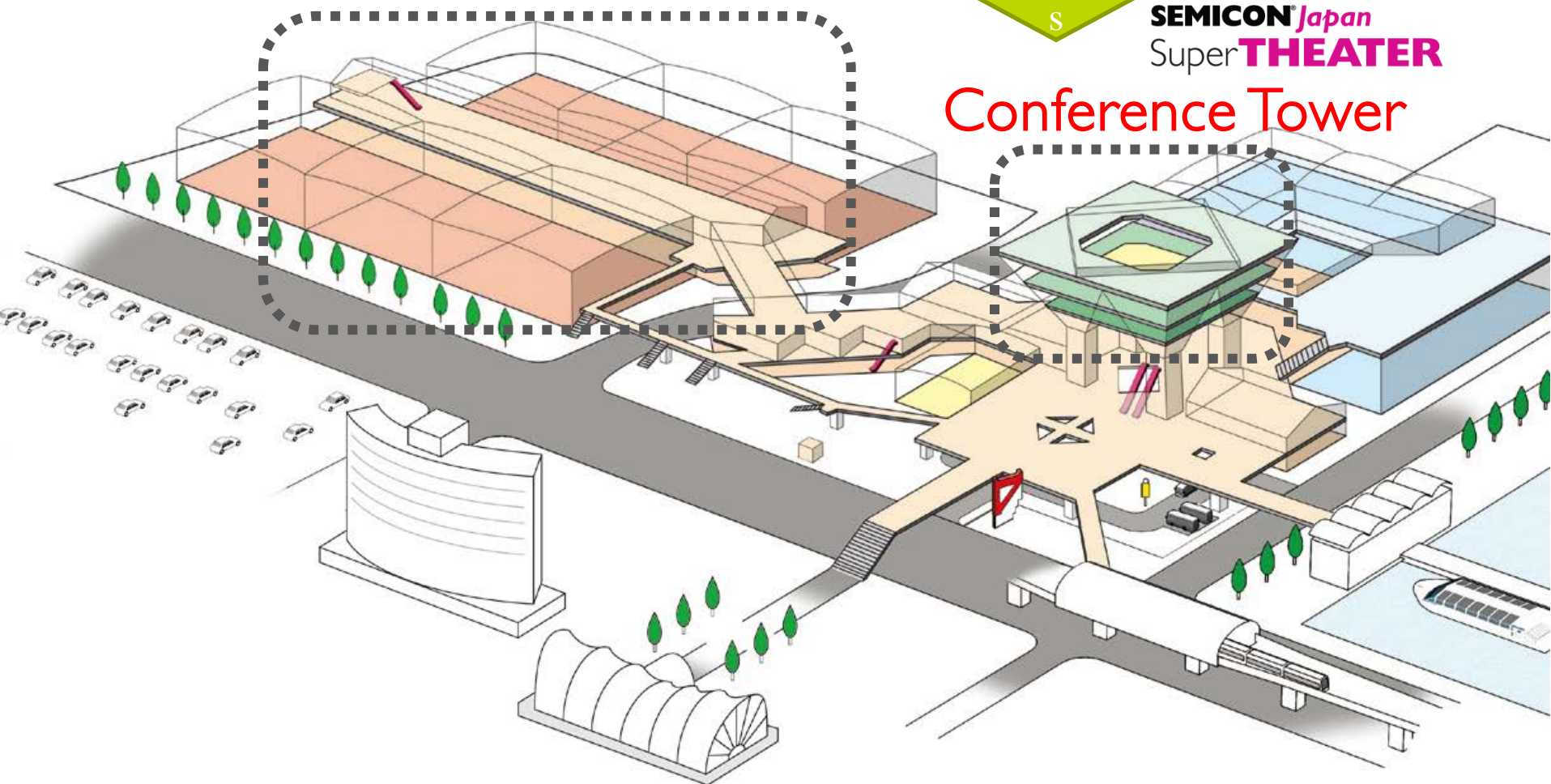
Tech**STAGE** SOUTH Tech**STAGE** NORTH

East Exhibition Halls 1~5

Standard  
Meeting  
Rooms

SEMICON Japan  
Super**THEATER**

Conference Tower



# Standards Meeting Schedule during SEMICON Japan 2015

- Location of standards meetings
  - December 14 and 15 → SEMI Japan Ichigaya Office
  - December 16-18 → Conference Tower, Tokyo Big Sight
- TC Chapter meetings
  - JRSC 12/15 (Tue) 16:30-19:00 /SEMI Japan
  - Gases & Facilities 12/15(Tue) 13:00-15:00 /SEMI Japan
  - Liquid & Chemicals 12/16(W) 10:30-12:00
  - PI&C 12/16(W) 14:00-17:00
  - Silicon Wafer 12/17 (Thu) 09:00-17:00
  - ISC 12/17(Thu) 13:30-16:30 (invitation only)
  - Traceability 12/18 (F) 10:00-12:00
  - I&C 12/18 (F) 10:00-17:00
  - EHS 12/18 (F) 10:00-17:00

# Standards Resection & Award Ceremony

## Friendship Party !!

December 17, Thursday

17:30-19:00 (door open: 17:15)

Room 605, Conference Tower

Tokyo Big Sight

# Congratulations!

## SEMI Japan Standards Award



Mitsuhiro Matsuda  
Hitachi Kokusai Electrics

## JRSC Special Appreciation Award



Yuko Toyoshima  
Hitachi High Technologies



Yoshihisa Takasaki  
SCREEN Semiconductor  
Solutions

# Staff Contact Information from Sept 1, 2015

Committee	Staff
Gases, Facilities, FPD M&C, FPD Meteorology, Liquid Chemical SIG: SEA, CGMG	<i>Naoko Tejima</i> <i>Manager, Standards &amp; EHS</i> <a href="mailto:ntejima@semi.org">ntejima@semi.org</a>
PI&C, I&C, Metrics, Traceability, PV, PV Materials, Packaging, 3DS-IC	<i>Chie Yanagisawa</i> <i>Sr. Coordinator, Standards &amp; EHS</i> <a href="mailto:cyanagisawa@semi.org">cyanagisawa@semi.org</a>
JRSC, SPI TF, Compound, Micropatterning, Silicon Wafer, EHS, AT, Test, EHS SIG: ESG, SMG, EHS	<i>Junko Collins</i> <i>Director, Standards &amp; EHS</i> <a href="mailto:jcollins@semi.org">jcollins@semi.org</a>
Others	Staff
Standards Products General Information, SEMIViews	<i>C. Yanagisawa</i>
Other Standards Operation,	<i>J. Collins</i>

Thank you